

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10078713	NAMIZUKA, YOSHIYUKI
	<b>Examiner</b>	<b>Art Unit</b>
	Dennis Rosario	2624

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
382	199	8/18/08	DR
	311	12/11/08	DR

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
East,all db	8/18/08	DR
IEEE-(((correct* <near/2> coefficient)<in>metadata)<and>(((edge or contour or outline) <near/5> (detect* or extract*))<in>metadata))-	8/18/08	DR
East, all db	12/11/08	DR
Google Scholar-user (coefficient or parameter or setting) mode threshold image (edge or contour or outline)-	12/11/08	DR

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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